



Sheet 1 of 2

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-1027-02	SERIAL NO. 10/774,371
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LIST OF DOCUMENTS CITED BY APPLICANT
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APPLICANT
Y. TAKAHASHI et al

FILING DATE
February 10, 2004

GROUP
1773 1762

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AB	AA 5,738,927	04/1998	Nakamura et al			
	AB 6,080,476	06/2000	Kanbe et al			
	AC 5,815,343	09/1998	Ishikawa et al			
	AD 6,168,861	01/2001	Chen et al			
AB	AE 5,939,202	08/1999	Ataka et al			
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AB	AL 10-269548	10/9/98	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AB	AR	JOURNAL OF MAGNETISM AND MAGNETIC MATERIALS, 152 (1996), "Effects of Pt addition on the magnetic and crystallographic properties of Co-Cr-Pt thin-film media", A. Ishikawa et al, pp. 265-273.
AB	AS	Nakatani, Y. and Hayashi, N., IEEE Trans. Mag., 34(4), 1998, 1618-1620.
AB	AT	Ikeda, Y., Sonobe, Y., Zeltzer, G., Yen, B., Takano, K., Do, H., Fullerton, E., and Rice, P., IEEE Trans. Mag., 37(4), 2001, 1583, 1585.

EXAMINER /Alain Bashore/ (01/03/2007)

DATE CONSIDERED

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LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKAHASHI et al			
				FILING DATE 2/10/04		GROUP <u>1773</u> <u>1762</u>	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS							
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	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i>							
AB	AR	Lu, B., Klemmer, T., Khizroev, S., Howard, J., Litvinov, D., Roy, A., and Laughlin, D., IEEE Trans. Mag., 37(4), 2001, 1319-1321.					
AB	AS	Yamanaka, K., Hamamoto, T., Nakano, Y. and Miura, M., IEEE Trans. Mag., 37(4), 2001, 1599-1601.					
AB	AT	Futamoto, M., Honda, Y., Hirayama, Y., Itoh, K., Ide, H., and Maruyama, Y., IEEE Trans. Mag., 32(5), 1996, 3789-3794.					
EXAMINER /Alain Bashore/ (01/03/2007)				DATE CONSIDERED			
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